



SOLON Corporation

Potential Induced Degradation

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NREL PVRW, February 1th, 2011



SOLON at a Glance



- One of the largest manufacturers of solar modules in Europe
- Large scale rooftop and greenfield installations
- Founded in 1997
- Production sites in Germany, Italy and the U.S.
- Employees: approx. 900

SOLON Corporation at a Glance



- 80 MW of annual manufacturing capacity in Tucson, AZ
- Large scale rooftop and Utility-scale installations
- Founded in 2007
- Wholly-owned subsidiary of SOLON SE
- Employees: approx. 150

Solar modules



Power plants

Industrial rooftops



Content

- Introduction & Motivation
- Background & Approach
- Results
 - Cell level
 - Panel level
 - System level
- What's Next?
- Summary & Conclusion

Motivation

Objective: To make Solar Energy even more competitive

→ Reduction of \$/kWh

→ Two approaches:

1. Reduction of \$/kWp

→ Become as cheap as possible!

2. Increase lifetime/ Decrease degradation

→ Become as stable/long-lasting as possible!

→ Both tracks have to be pursued in parallel ...

Potential Induced Degradation

- Power degradation due the exposure to an external potential
 - External potential = Potential relative to ground
- High Voltage Stress

= Power Degradation caused by the exposure to a potential relative to ground, and dependent on its magnitude and sign

- Two cases: Reversible (Polarization)
Irreversible (Electro corrosion)

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Background

- First addressed by Hoffman and Ross (JPL) 1978: Impact of voltage-biased humidity exposure of solar panels on long term stability – “Bias Humidity test... as a candidate for module qualification”
- Prominent cases such as Sunpower’s Polarization effect
- More recently NREL: Degradation caused by HVS not covered by IEC or UL standards right now
- Increasing importance because:
 - Increasing need to push down overall degradation
 - Increasing system voltages
 - Increasing variety of solar cell technologies

Approach

Objective: Minimizing / Avoiding PID

→ On cell level



→ On panel level

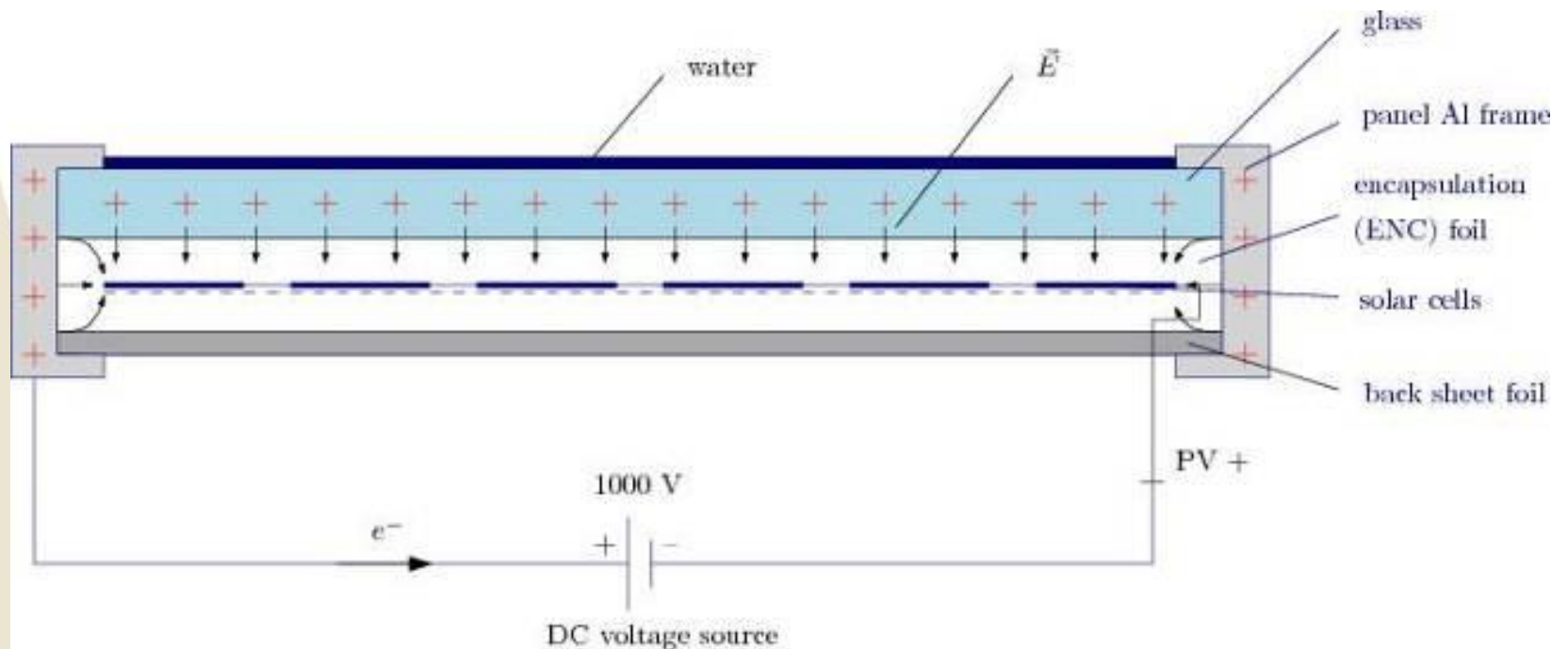


→ On system level



Test Set up

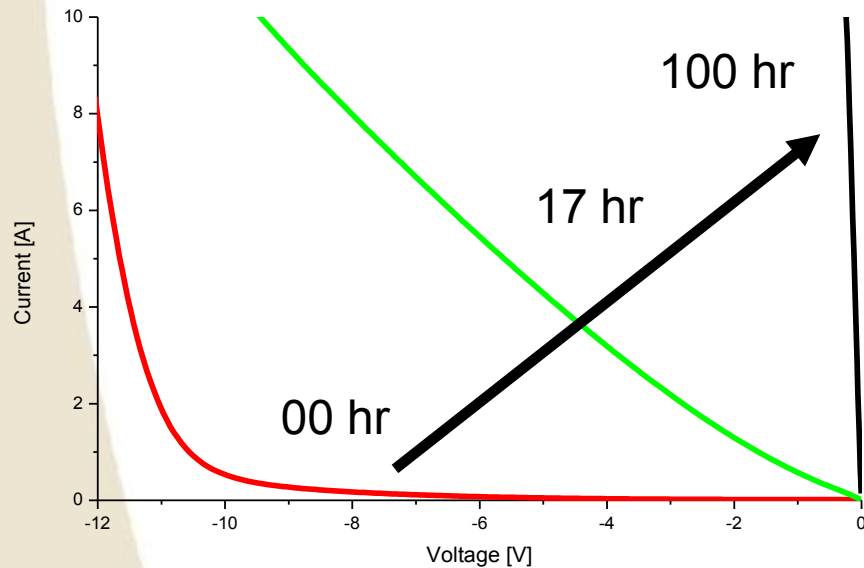
- Worst case scenario
- Simulation of potential relative to ground



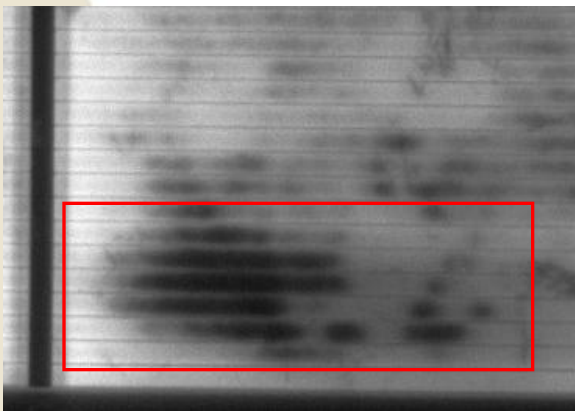
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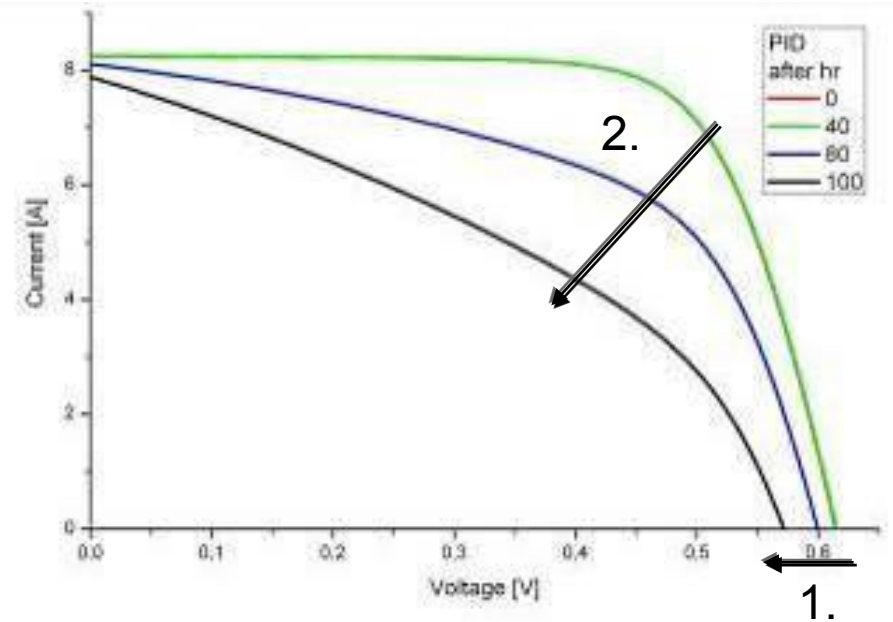
Cell Level



- Decrease of overall shunt resistance



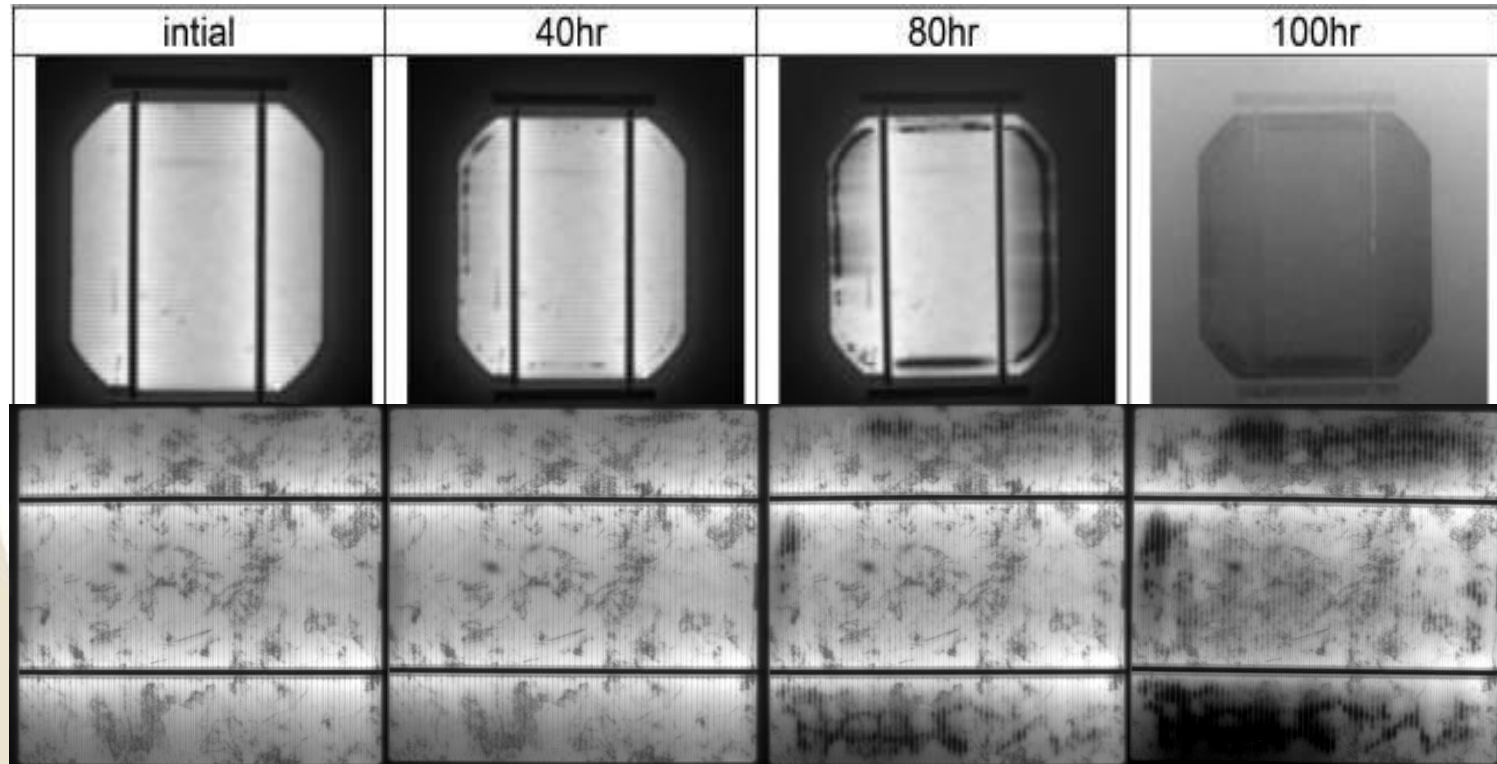
→ Local short circuit of the pn-junction



→ 1. Loss FF

→ 2. Loss in open circuit voltage

Cell Level



EL images of a cell during PID test (1000V, 100h)

Tendency for PID very different for different cell manufacturers

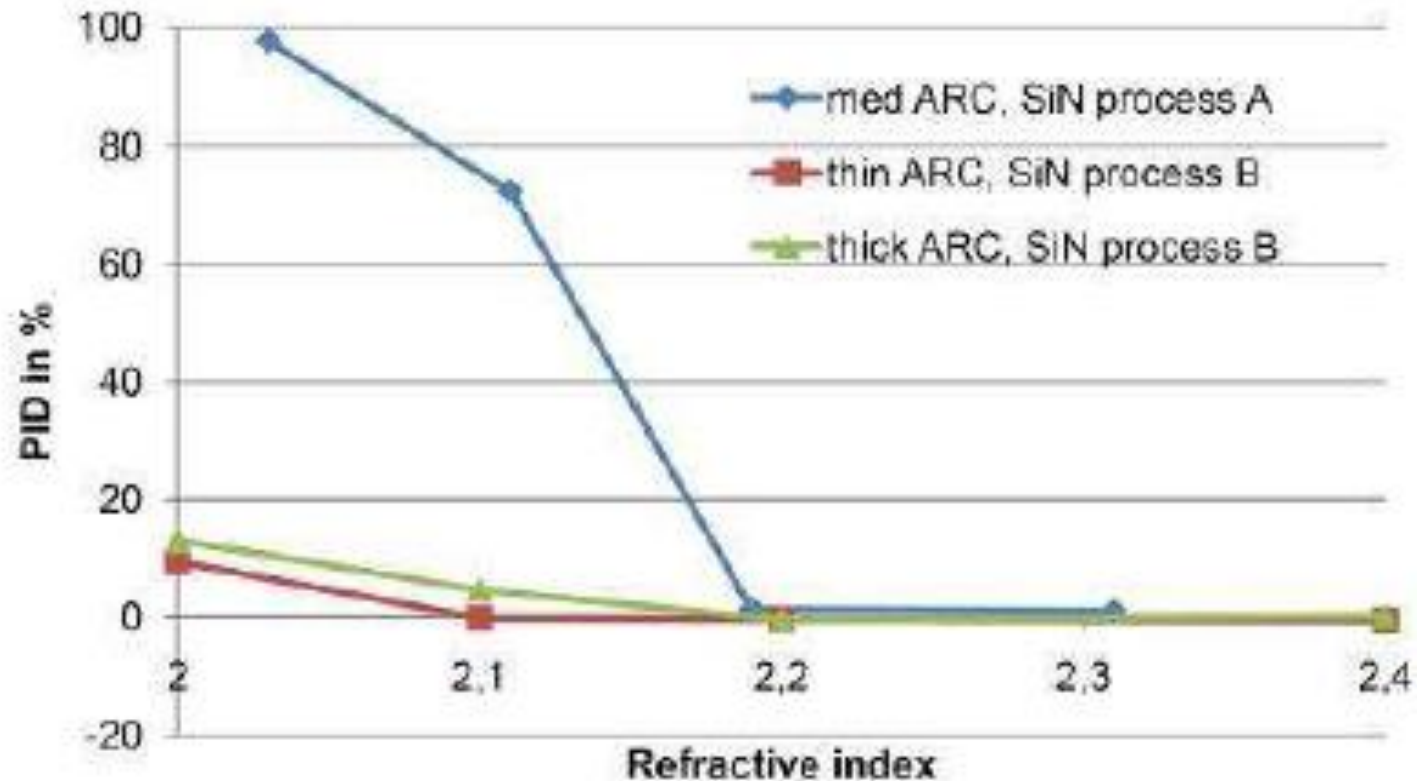
→ Impact factors on cell level?

Cell Level

Impact factors:

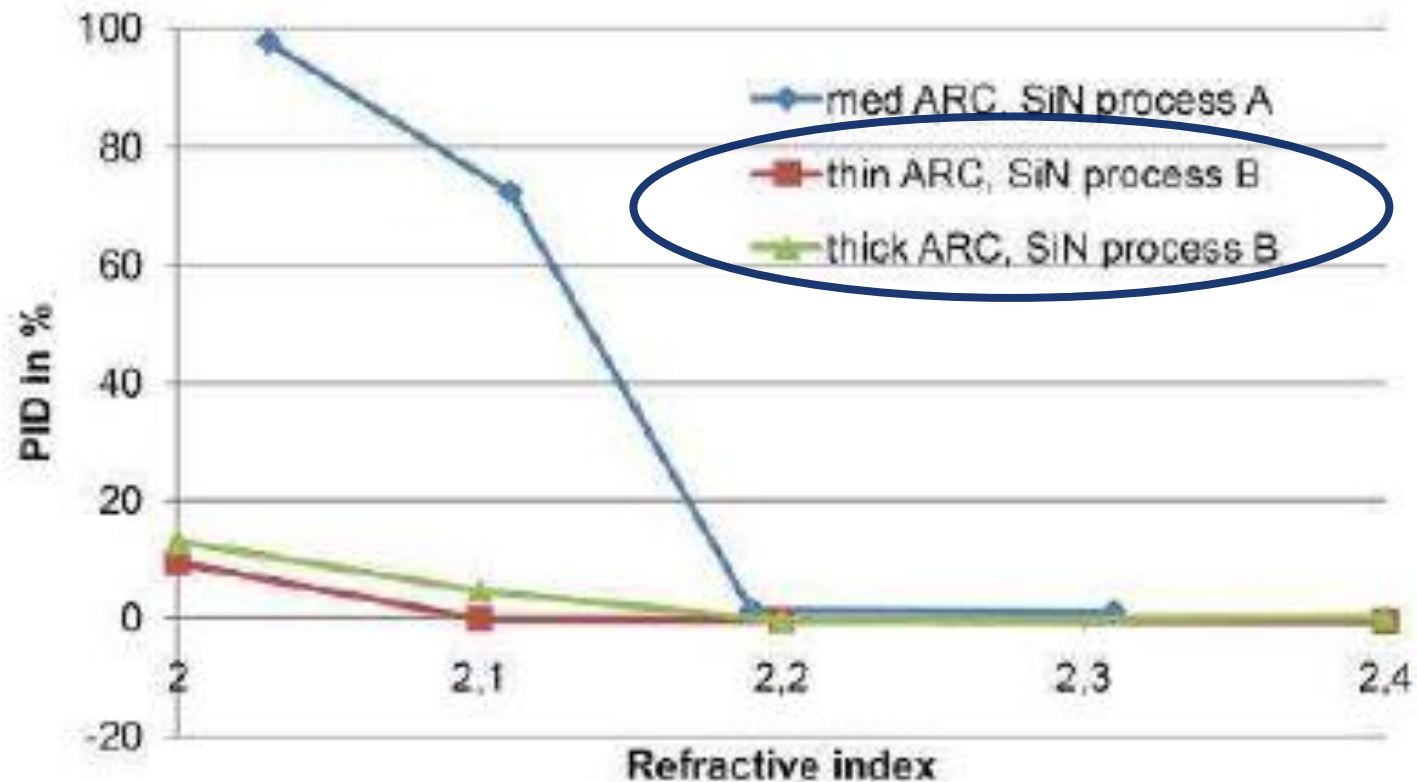
- Base resistivity of wafer material → significant influence
- Emitter sheet resistivity → significant influence
- **ARC deposition → key feature**
 - Ratio of Si to N
 - Thickness
 - Homogeneity

Cell Level



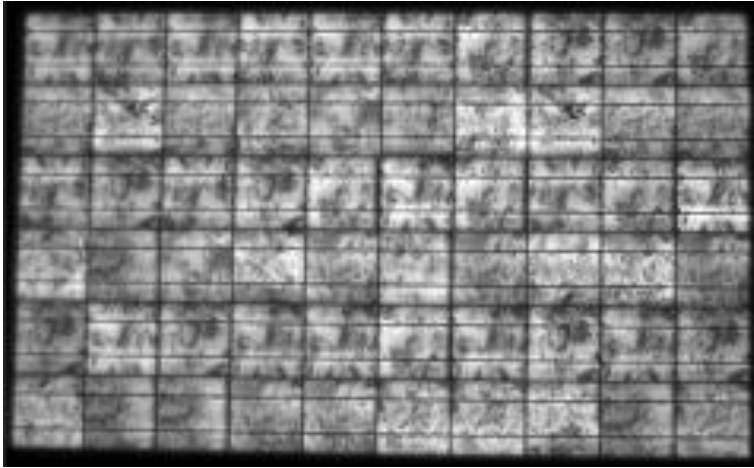
**By choosing suitable parameters for ARC deposition
PID can be minimized/ stopped on cell level**

Cell Level



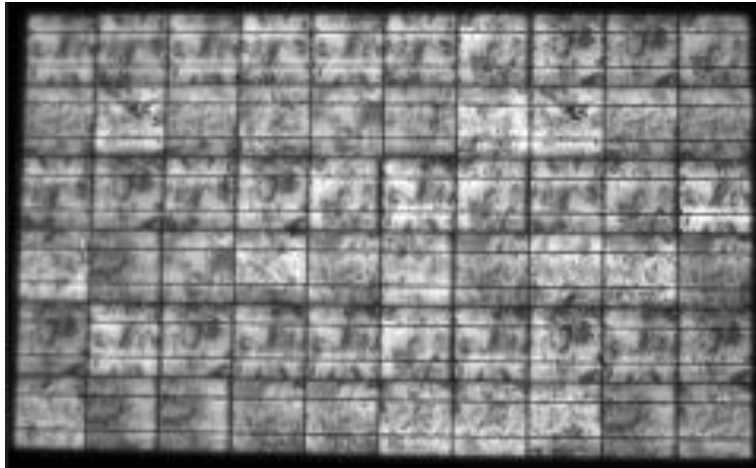
**By choosing suitable parameters for ARC deposition
PID can be minimized/ stopped on cell level**

Panel level

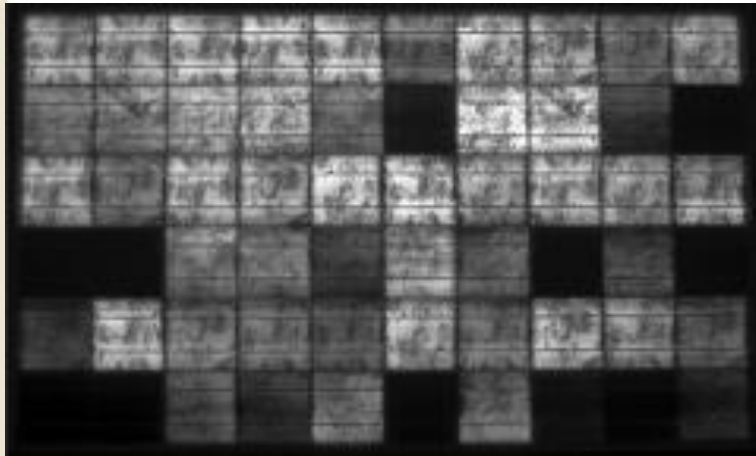


EL image of a panel before
100hr 1000V PID...

Panel level



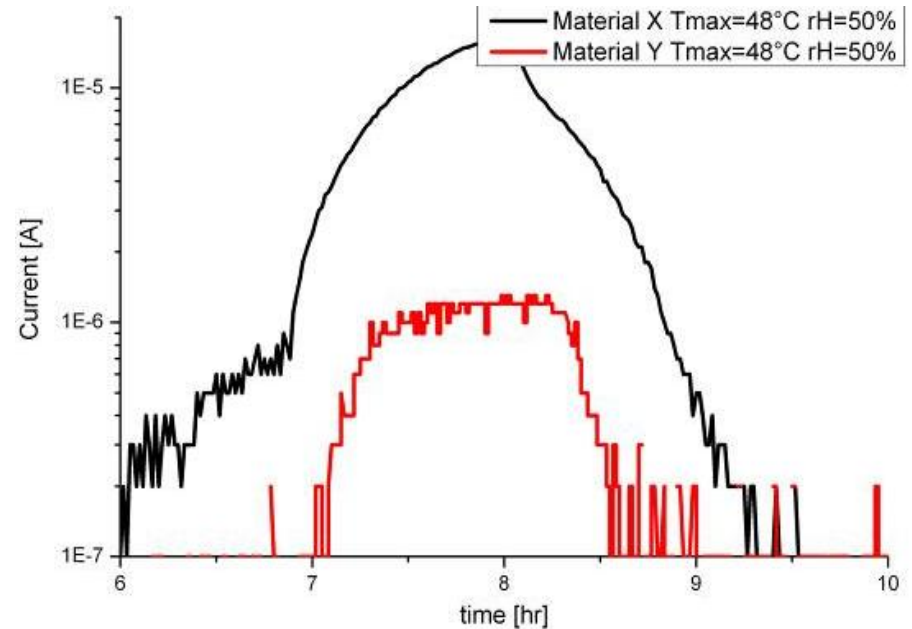
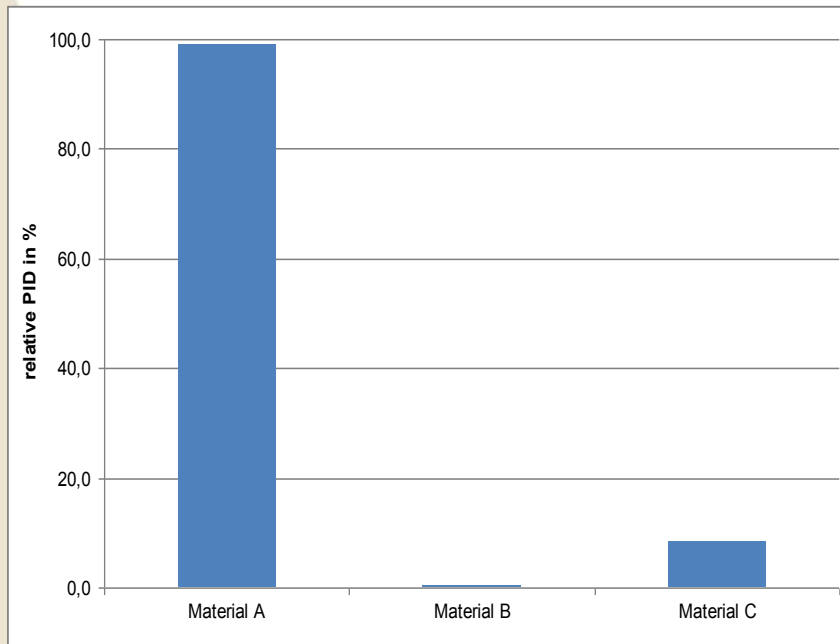
EL image of a panel before
100hr 1000V PID...



...and after.

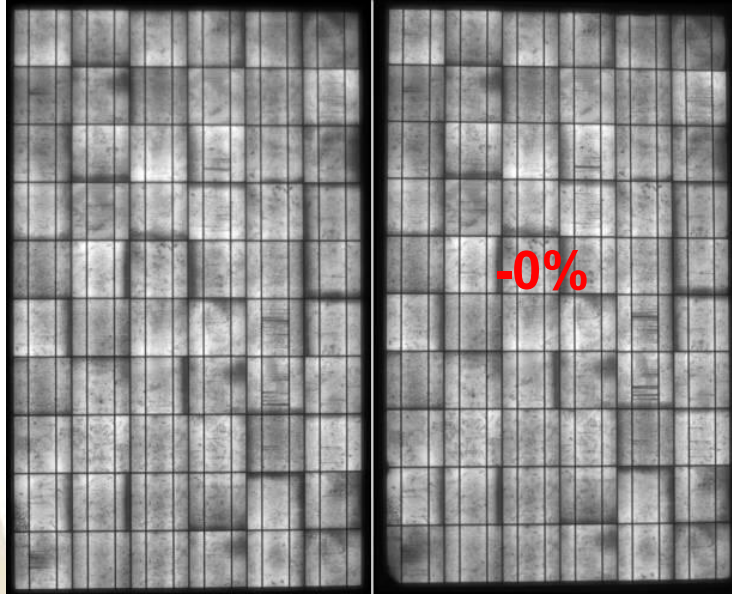
Key feature: Leakage current

Panel level I



**PID can be stopped/ minimized on panel level
by minimizing leakage current → Choice of suitable encapsulation**

Panel level II



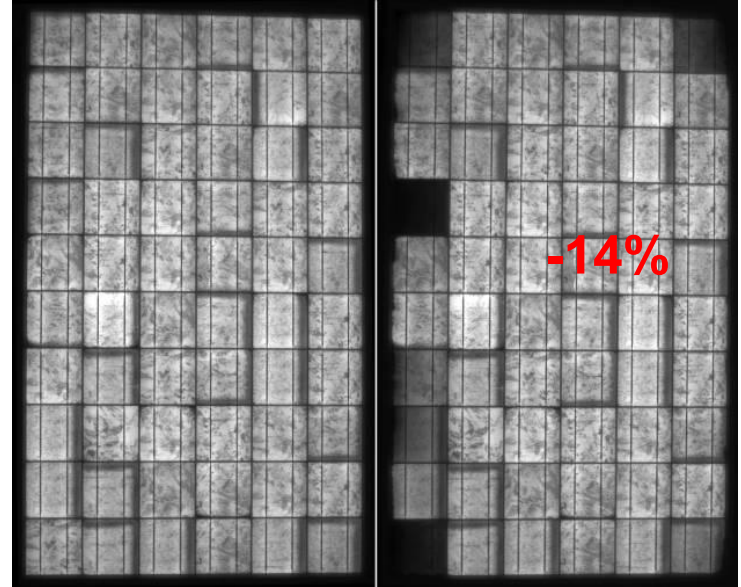
Time: 100h

Voltage: 1000V

Temperature: 48°C

Humidity: 50%

Material: X



Time: 100h

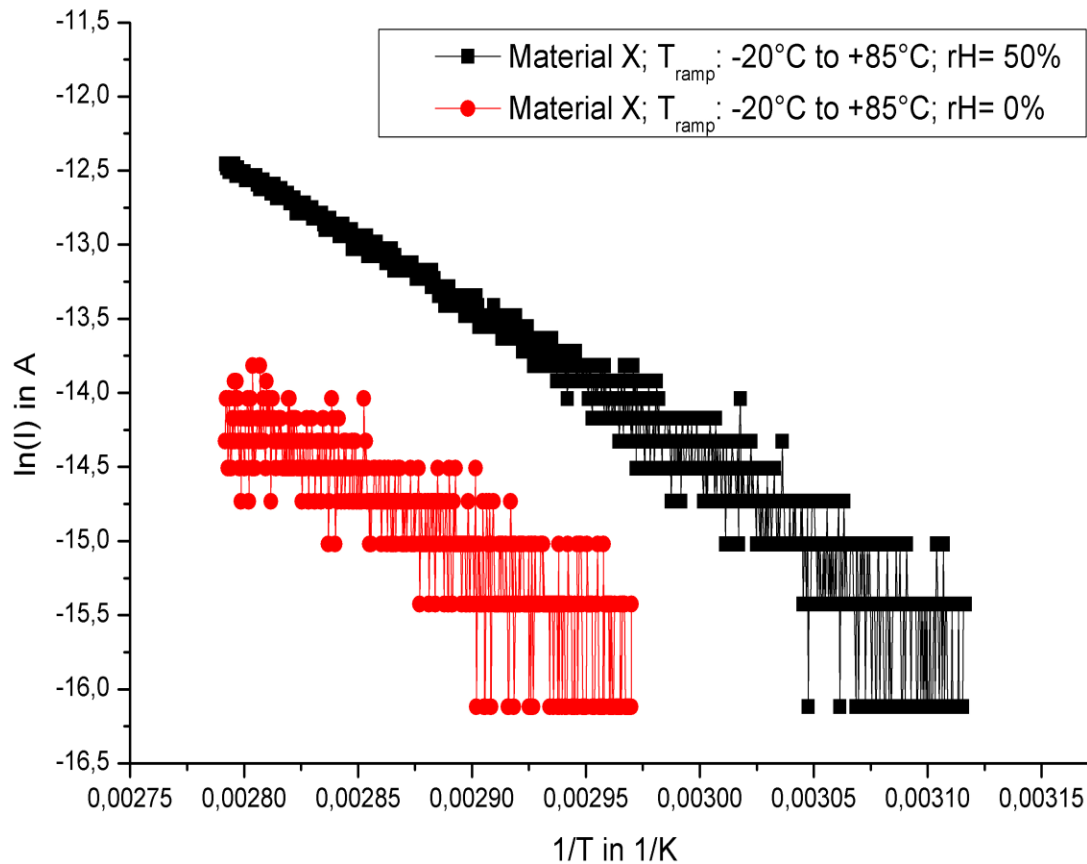
Voltage: 1000V

Temperature: 48°C

Humidity: 50%

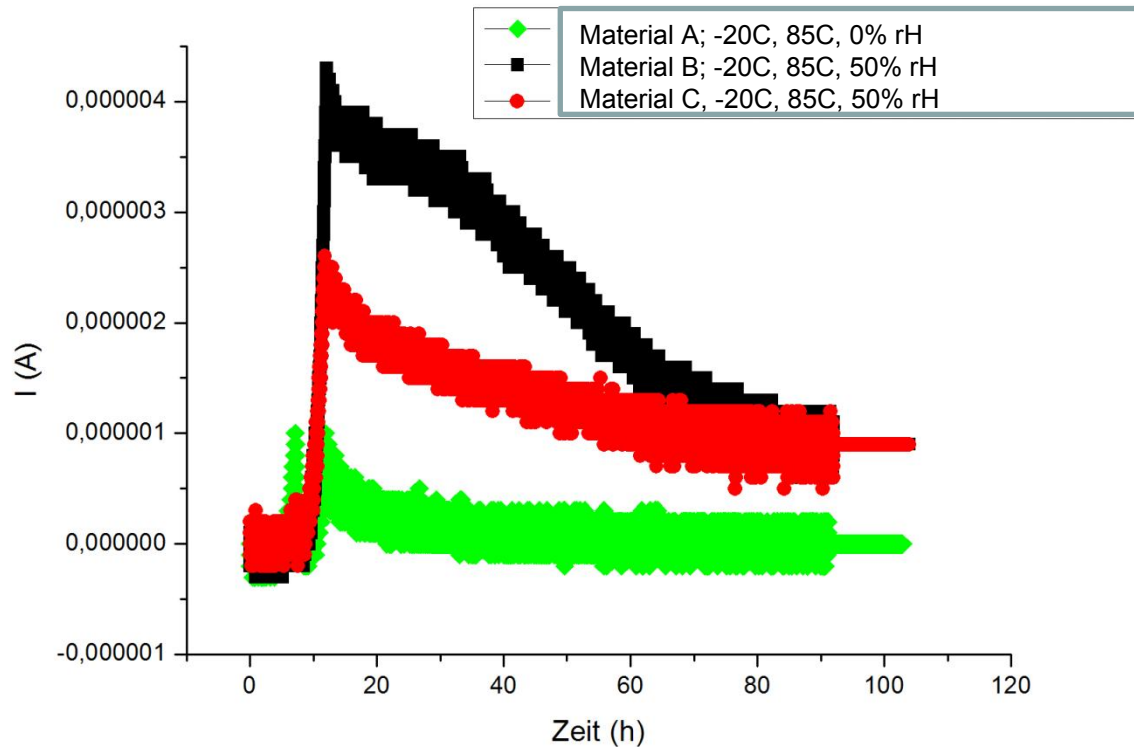
Material: Y

Panel level



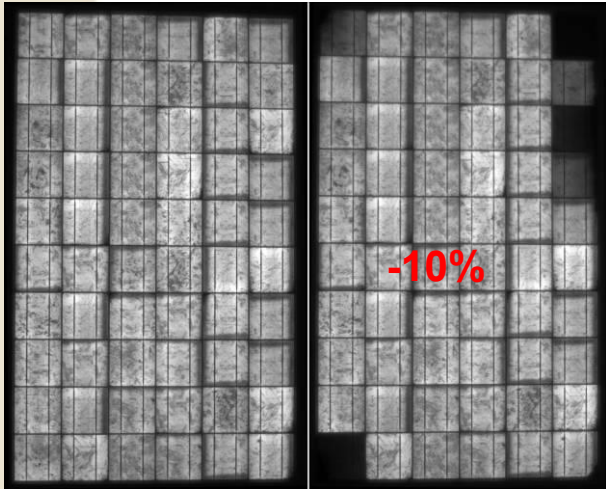
Leakage current and cooresponding PID strongly dependent on temperature and humidity

Panel level



Leakage current and cooresponding PID strongly dependent on temperature and humidity

Temperature and humidity

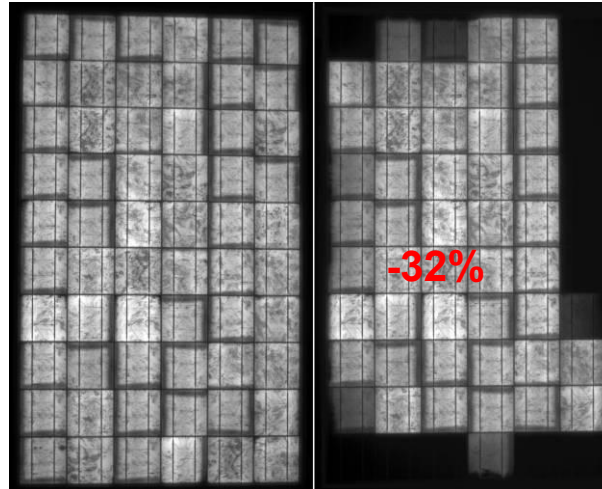


Time: 100h

Voltage: 1000V

Temperature: 85°C

Humidity: $\approx 0\%$

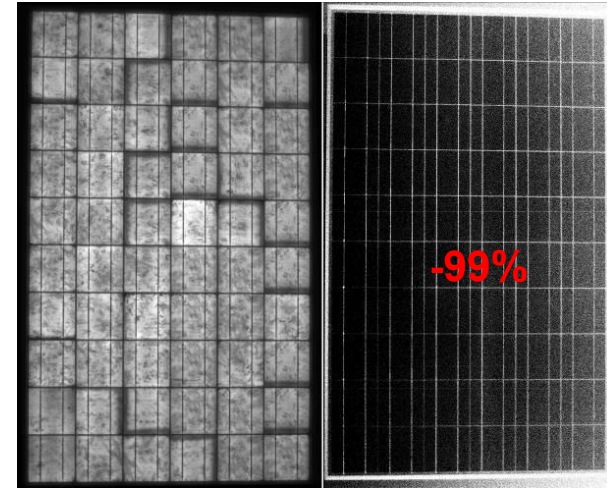


Time: 100h

Voltage: 1000V

Temperature: 85°C

Humidity: 50%



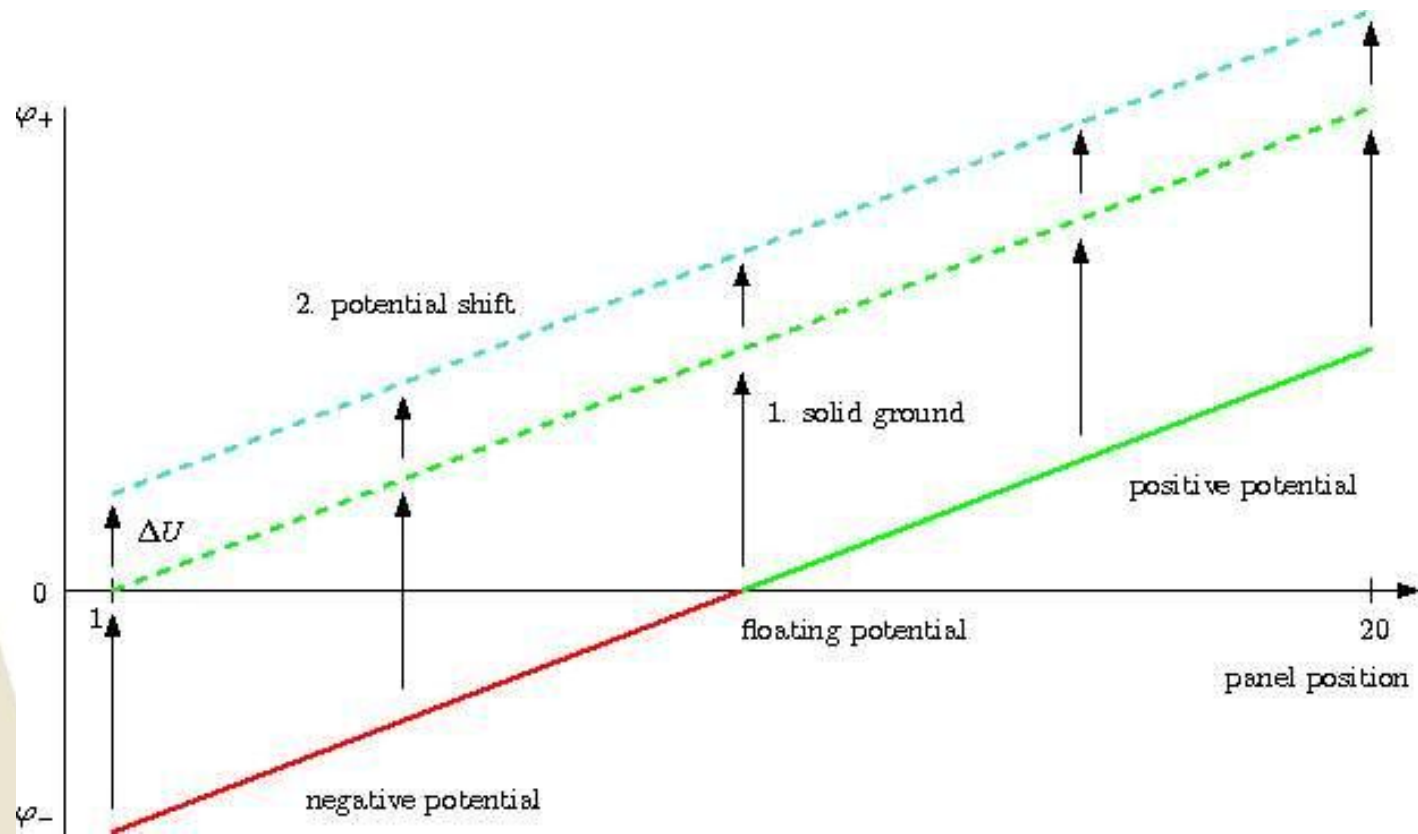
Time: 100h

Voltage: 1000V

Temperature: 85°C

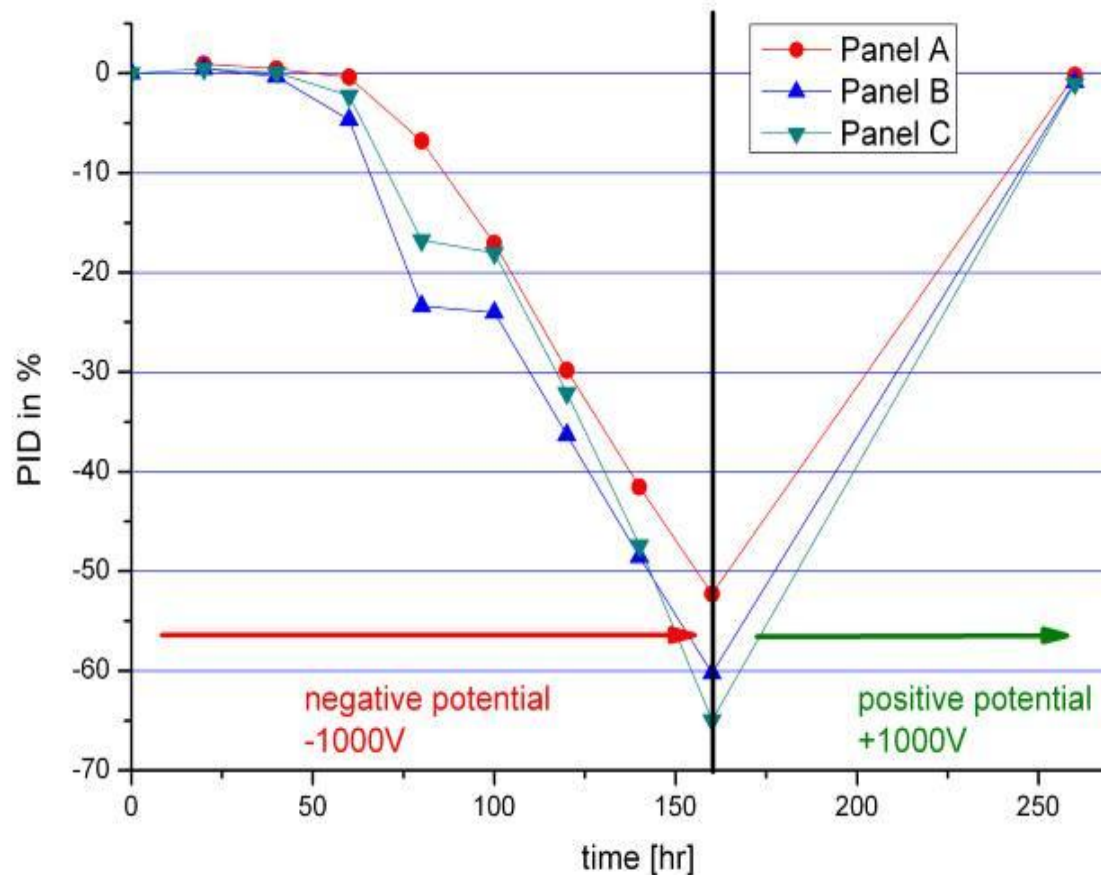
Humidity: 100%

System level



→ Potential relative to ground is determined by grounding configuration

System level



Degradation and recovery of panels in the lab

**PID can be stopped/ reversed by avoiding a negative potential
→ Suitable grounding configuration**

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What's next?

How do laboratory results correlate to real life?

The concept:

- 2 different types of “laboratory proven” PID panels
 - High PID tendency
 - Low PID tendency
- 3 different climatic regions

The need:

- 3 identical test sites in 3 different regions

Global Test Site Network

Outdoor Test Sites and Proving Grounds

Providing the unique ability to test modules and related technologies in three distinct climatic regions

- 3 Identical sites worldwide
- 4 Components each site
 1. Dual-Axis Tracker
 2. Single-Axis Tracker
 3. Fixed-Tilt 32°
 4. Fixed-Tilt 5°
- 6 inverters each Component

Total Capacity: **72** individual strings

Individually Monitoring:

DC Power
AC Power

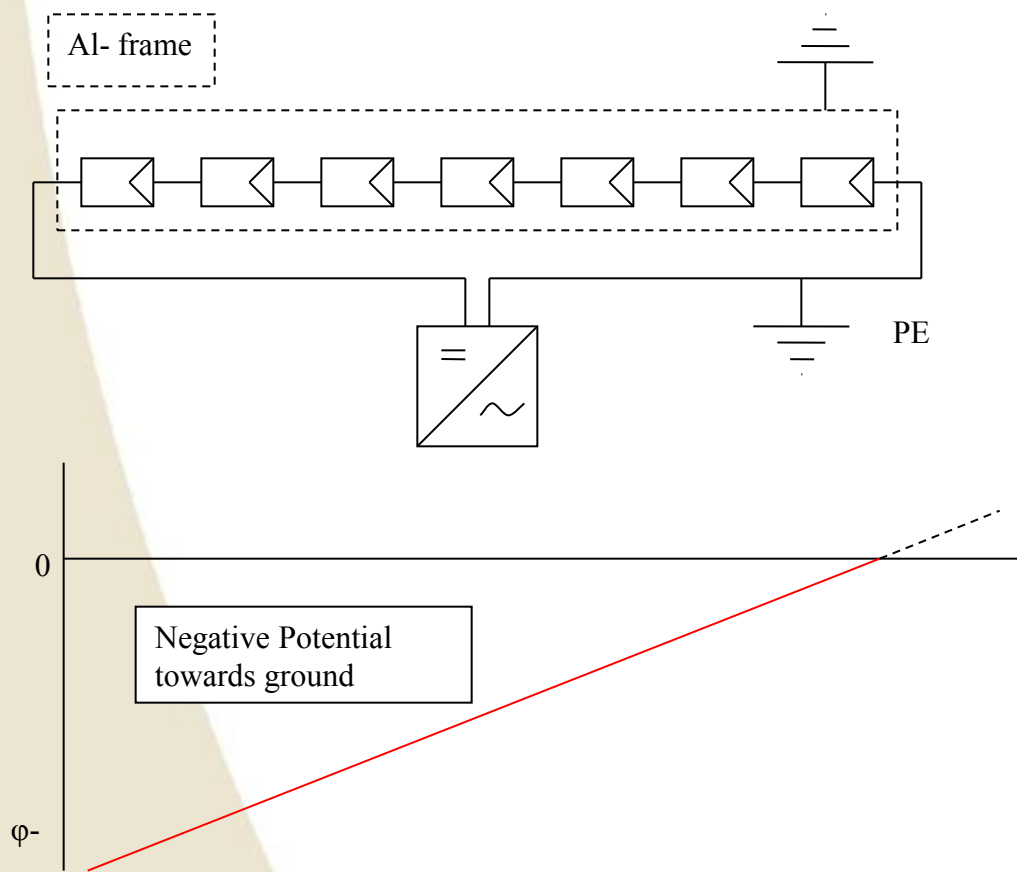
Irradiance (in plane & global)
Ambient temp
Cell temp
Humidity
Wind speed

Global Test Site Network – The Locations



What's next?

Setup on test sites:



- 3 test sites with identical system configuration and technology
- 2 strings of 7 modules each site – total 6 strings
- Two different materials (high and low PID tendency)
- Positive pole is grounded to simulate the worst case scenario
- Meteorological stations log environmental conditions at the different test sites

What's next?



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What's next?

Solar Cell Level

→ Cooperation with different cell suppliers to modify the ARC according to cell spec

Module Level

→ Electrical characterization of encapsulation foils with high and low PID prevention

System Level

→ Evaluating suitable inverter suppliers and proposed solutions

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Summary and Conclusion

- Origin of PID: Properties of solar cell
 - PID can be excluded/minimized on cell level
 - ARC
- Leakage current on panel level key feature for PID
 - PID can be excluded/ minimized on panel level
 - Encapsulation
- Sign and magnitude of the external potential critical for PID
 - PID can minimized on system level
 - Grounding
- Avoiding PID on panel level favourable since
 - Independent of cell technology
 - Independent of system / grounding configuration

Acknowledgements

Juliane Berghold

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& Different cell suppliers for providing us with specific test cells !!



Thank you for your attention!

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